

FIG. 1A

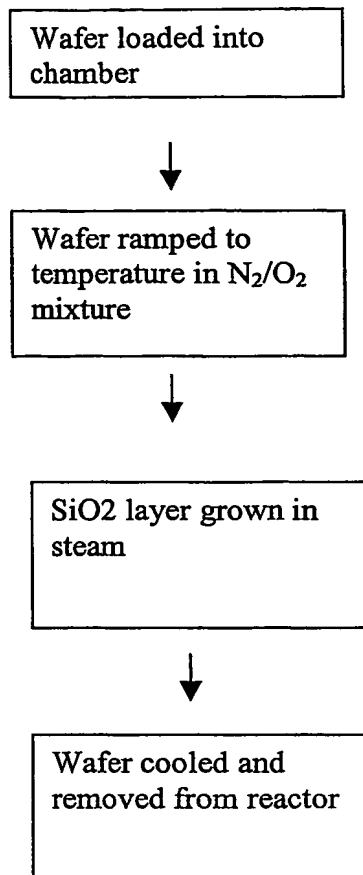
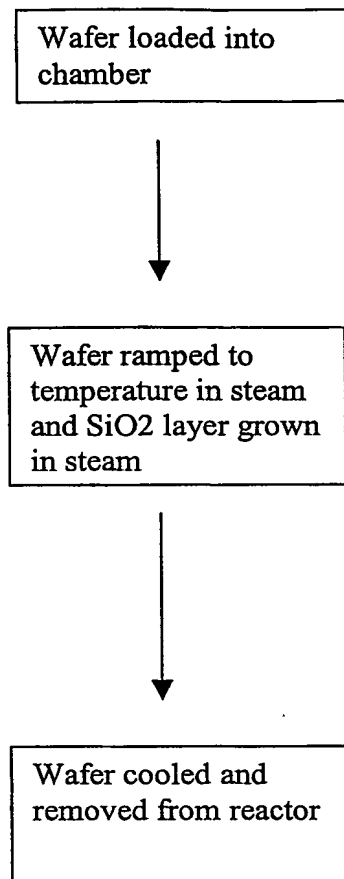
Prior Art

FIG. 1B

Present Invention

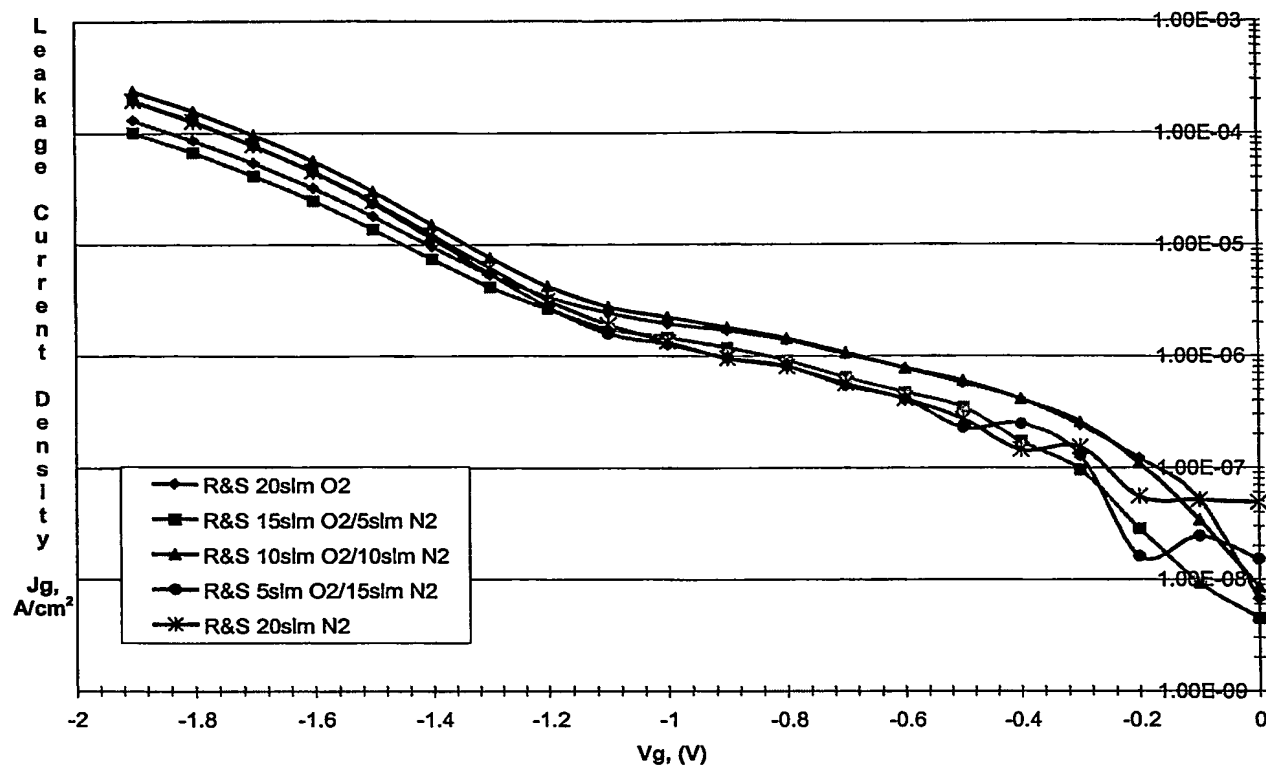


FIG. 2
Leakage Current Density vs V_g Charts for 900°C Wet Oxidation Using Various Oxygen Flows During Ramp & Stabilization Step as practiced in the prior art.

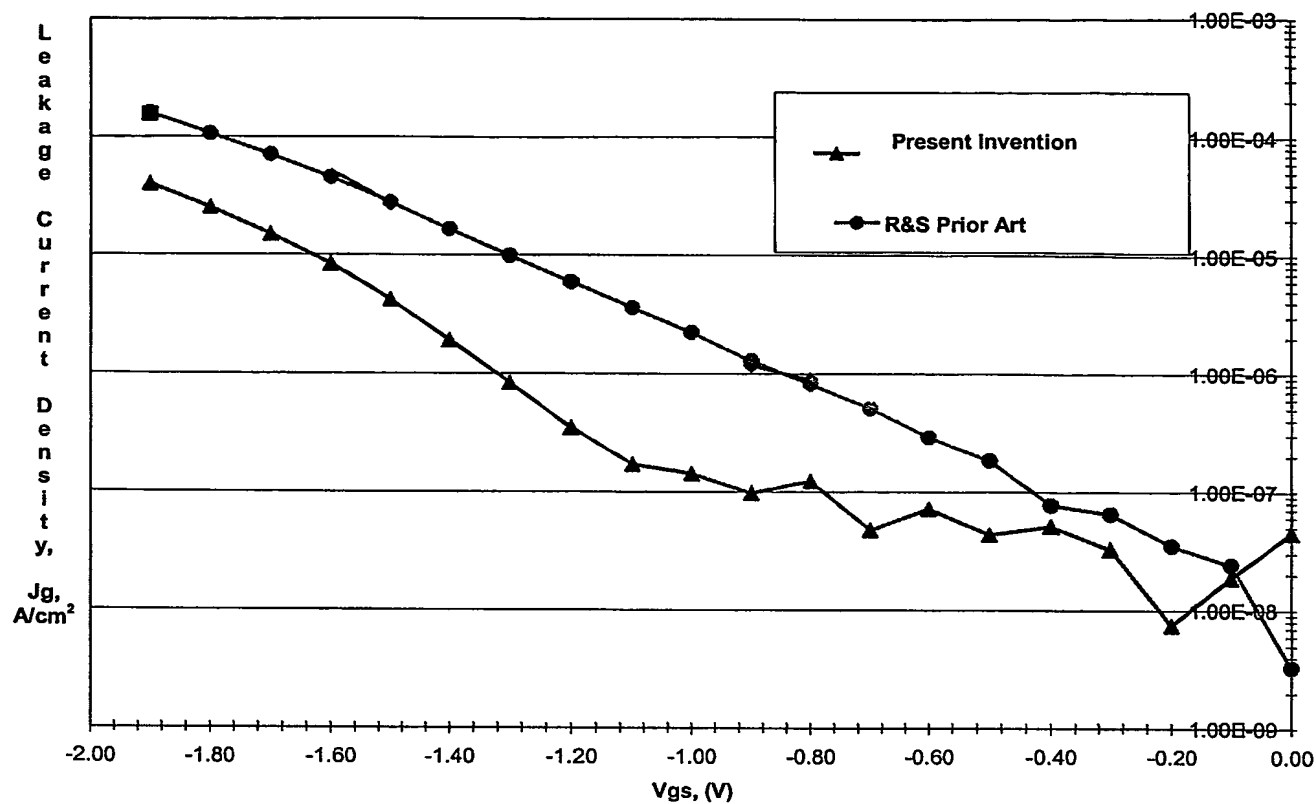


FIG. 3
Leakage current density (J_g) vs V_{gs} for wet oxidation processes at different process temperatures.

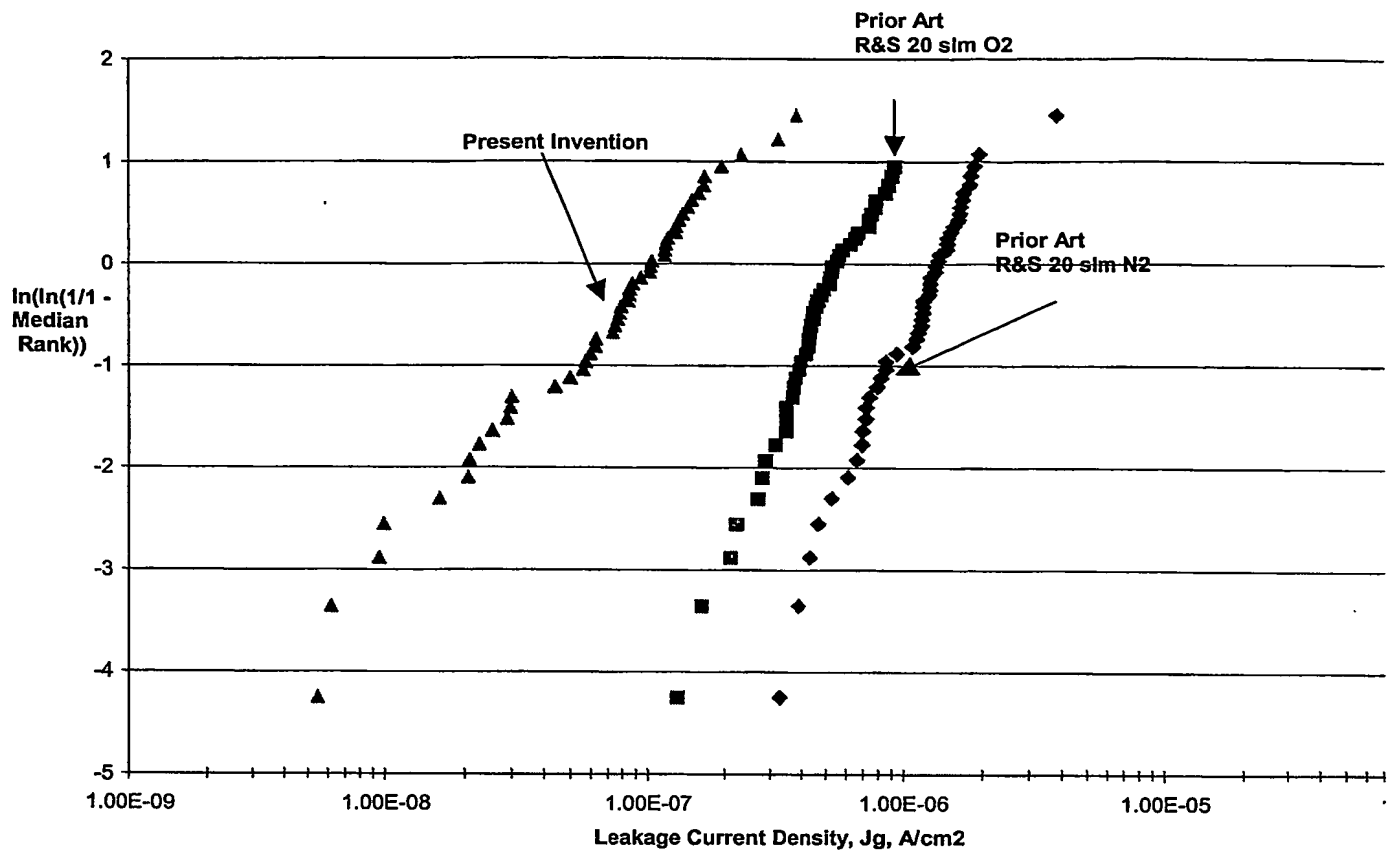


FIG. 4
Weibull plots for wet oxidation processes with and without ramp and stabilization step at 900°C